Applicant(s)/Patent Under Reexamination Application/Control No. SAMUELSON ET AL. 10/751,943 Notice of References Cited Art Unit Examiner Page 1 of 1 2891 Matthew W. Such

U.S. PATENT DOCUMENTS

	U.S. PATENT DOCUMENTO							
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification			
*			04-2002	Hantschel et al.	216/2			
		US-2002/0040884		Lu et al.	117/104			
*	В	US-2003/0213428	11-2003		438/378			
*	С	US-6,913,982	07-2005	Lim et al.	73/105			
*	D	US-2002/0178799	12-2002	Kitazawa et al.	250/306			
*	E	US-6,011,261	01-2000	Ikeda et al.	250/500			
	F	US-						
	G	US-						
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NON-PATENT DOCUMENTS

	NON-PATENT DOCUMENTS					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Snow, Campbell and Novak. Applied Physics Letters. 80 (2002): 2002-2004.				
	v	Dai and Franklin. Applied Physics Letters. 73 (1998): 1508-1510.				
	w	Rao, Eklund, Bandow, Thess and Smalley. Nature. 388 (1997): 257-259.				
	x	Lee, Kim, Fischer, Thess and Smalley. Nature. 388 (1997) 255-257.				
1	l	11 N: Office option (See MPEP 5 707 05(a).)				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.